Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/617,230	KIM ET AL.	
Examiner	Art Unit	
Jonathan S. Creneau	1746	

	SEAR	CHED	
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED				
Class	Subclass	Date ·	Examiner	
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DATE 5/18/2006	JC
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